Application/Control No. Applicant(s)/Patent Under Reexamination 10/664,106 CHANG ET AL. **Notice of References Cited** Art Unit Examiner Page 1 of 1 1745 Julian Mercado **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name Country Code-Number-Kind Code MM-YYYY 429/127 US-5,582,931 12-1996 Kawakami, Soichiro Α US-5,225,296 07-1993 Ohsawa et al. 429/213 В US-С US-D US Ε ÚS-F US-US-Н US-US-J US-Κ US-US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY H01M 2/16 WO 97/08763 03-1997 Yamashita et al. Ν 0 Р Q R s Т NON-PATENT DOCUMENTS Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W Х *A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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